

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/057,204 | Applicant(s)/Patent Under Reexamination AYRES ET AL. | |
| | Examiner Ranodhi Serrao | Art Unit 2141 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-2002/0065730 | 05-2002 | Nii, Naoaki | 705/26 |
| | B | US-5,734,589 | 03-1998 | Kostreski et al. | 715/716 |
| | C | US-2003/0191816 | 10-2003 | Landress et al. | 709/219 |
| | D | US-2002/0058499 | 05-2002 | Ortiz, Luis M. | 455/412 |
| | E | US-5,948,040 | 09-1999 | DeLorme et al. | 701/201 |
| | F | US-5,734,719 | 03-1998 | Tsevdos et al. | 700/234 |
| | G | US-5,781,909 | 07-1998 | Logan et al. | 707/200 |
| | H | US-5,949,411 | 09-1999 | Doerr et al. | 715/716 |
| | I | US-6,032,130 | 02-2000 | Alloul et al. | 705/27 |
| | J | US-5,948,404 | 09-1999 | Taketomo et al. | 424/115 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.